

Notice of References Cited

Application/Control No.

10/509,067

Applicant(s)/Patent Under
Reexamination
FINKELSTEIN ET AL.

Examiner

Christopher A. Revak

Art Unit

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2008/0295180	11-2008	Yoneda, Takeshi	726/27
*	B	US-2007/0061581	03-2007	Holtzman et al.	713/176
*	C	US-6,901,385	05-2005	Okamoto et al.	705/51
*	D	US-2008/0301469	12-2008	Plouffe et al.	713/193
*	E	US-2008/0301468	12-2008	Murase et al.	713/193
*	F	US-2008/0301440	12-2008	Plouffe et al.	713/164
*	G	US-2008/0298581	12-2008	Murase et al.	380/44
*	H	US-2007/0006294	01-2007	Hunter, G. Kenneth	726/014
*	I	US-2006/0015748	01-2006	Goto et al.	713/190
*	J	US-2005/0262342	11-2005	Field, Scott A.	713/165
*	K	US-2002/0129245	09-2002	Cassagnol et al.	713/168
*	L	US-6,438,666	08-2002	Cassagnol et al.	711/163
*	M	US-6,385,727	05-2002	Cassagnol et al.	713/193

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
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	V					
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	X					

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